

<b>Notice of References Cited</b>	Application/Control No. 10/080,449	Applicant(s)/Patent Under Reexamination BLAKE ET AL.	
	Examiner Anthony Mackowey	Art Unit 2623	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,307,965	10-2001	Aggarwal et al.	382/225
	C	US-2003/0123737	07-2003	Mojsilovic et al.	382/224
	D	US-5,867,584	02-1999	Hu et al.	382/103
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	J	US-5,389,790	02-1995	Honey et al.	250/342
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Walpole, Ronald E. and Myers, Raymond H., "Probability and Statistics for Engineers and Scientists", 1978, Macmillan Publishing Co., Inc., 2nd Ed., pp. 128-131
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.